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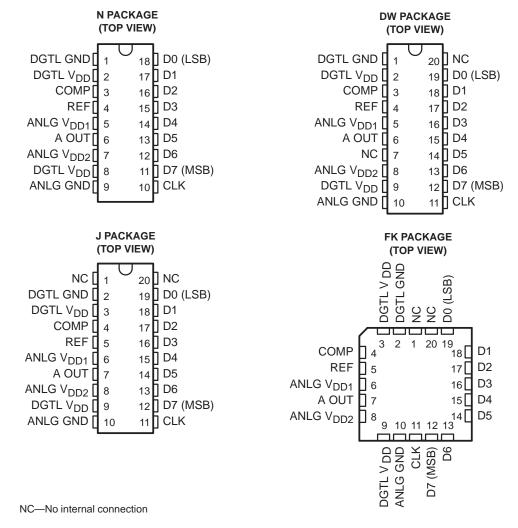
- 8-Bit Resolution
- ±0.2% Linearity
- Maximum Conversion Rate
   30 MHz Typ
   20 MHz Min
- Analog Output Voltage Range V<sub>DD</sub> to V<sub>DD</sub> –1 V

- TTL Digital Input Voltage
- 5-V Single Power-Supply Operation
- Low Power Consumption . . . 80 mW Typ
- Interchangeable With Fujitsu MB40778

#### description

The TLC5602x devices are low-power, ultra-high-speed video, digital-to-analog converters that use the LinEPIC™ 1-µm CMOS process. The TLC5602x converts digital signals to analog signals at a sampling rate of dc to 20 MHz. Because of high-speed operation, the TLC5602x devices are suitable for digital video applications such as digital television, video processing with a computer, and radar-signal processing.

The TLC5602C is characterized for operation from 0°C to 70°C. The TLC5602M is characterized over the full military temperature range of –55°C to 125°C.



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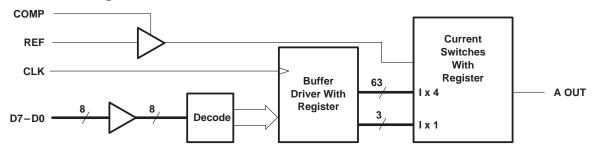


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#### **AVAILABLE OPTIONS**

PACKAGE								
TA	WIDE-BODY SMALL OUTLINE (DW)	CERAMIC CHIP CARRIER (FK)	CERAMIC DIP (J)	PLASTIC DIP (N)				
0°C to 70°C	TLC5602CDW			TLC5602CN				
-55°C to 125°C		TLC5602MFK	TLC5602MJ					

#### functional block diagram



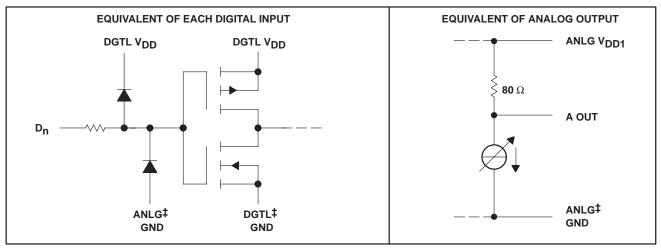
#### **FUNCTION TABLE**

TONCTION TABLE										
STEP	DIGITAL INPUTS								OUTPUT	
	D7	D6	D5	D4	D3	D2	D1	D0	VOLTAGE†	
0	L	L	L	L	L	L	L	L	3.980 V	
1	L	L	L	L	L	L	L	Н	3.984 V	
					1				I	
127	L	Н	Н	Н	Н	Н	Н	Н	4.488 V	
128	Н	L	L	L	L	L	L	L	4.492 V	
129	Н	L	L	L	L	L	L	Н	4.496 V	
					1				1	
254	Н	Н	Н	Н	Н	Н	Н	L	4.996 V	
255	Н	Н	Н	Н	Н	Н	Н	Н	5.000 V	

 $\dagger$  V<sub>DD</sub> = 5 V and V<sub>ref</sub> = 4.02 V

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#### schematics of equivalent input and output



<sup>‡</sup> ANLG GND and DGTL GND do not connect internally and should be tied together as close to the device terminals as possible.

#### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, ANLG V <sub>DD</sub> , DGTL V <sub>DD</sub>	0.5 V to 7 V
Digital input voltage range, V <sub>I</sub>	0.5 V to 7 V
Analog reference voltage range, V <sub>ref</sub>	$V_{DD} - 1.7 \text{ V to } V_{DD} + 0.5 \text{ V}$
Operating free-air temperature range, T <sub>A</sub> : TLC5602C	0°C to 70°C
TLC5602M	–55°C to 125°C
Storage temperature range, T <sub>stg</sub>	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

			MIN	NOM	MAX	UNIT	
Supply voltage, V <sub>DD</sub>			4.75	5	5.25	V	
Analog reference voltage, V <sub>ref</sub>					4.2	V	
High-level input voltage, VIH			2			V	
Low-level input voltage, V <sub>IL</sub>					0.8	V	
Pulse duration, CLK high or low, t <sub>W</sub>			25			ns	
Setup time, data before CLK↑, t <sub>SU</sub>			16.5			ns	
Hold time, data after CLK↑, th						ns	
Phase compensation capacitance, C <sub>comp</sub> (see Note 1)						μF	
Load resistance, R <sub>L</sub>			75k			Ω	
On creating from air temporature T.	TLC5602C		0		70	°C	
Operating free-air temperature, T <sub>A</sub>	TLC5602M		-55		125		

NOTE 1: The phase compensation capacitor should be connected between COMP and ANLG GND.



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## electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER			TEST CONDITIONS			MIN	TYP‡	MAX	UNIT
lн	High-level input current	Digital	V <sub>I</sub> = 5 V			±1	μΑ		
Ι <sub>Ι</sub> L	Low-level input current	inputs	V <sub>I</sub> = 0 V			±1	μΑ		
I <sub>ref</sub>	Input reference current	V <sub>ref</sub> = 4 V					10	μΑ	
VFS	Full-scale analog output ve	$V_{DD} = 5 \text{ V}, \qquad V_{ref} = 4.02 \text{ V}$			V <sub>DD</sub> -15	V <sub>DD</sub>	V <sub>DD</sub> +15	mV	
			V <sub>DD</sub> = 5 V, V		TLC5602C	3.919	3.98	4.042	
Vzs	Zero-scale analog output	Zero-scale analog output voltage		$V_{ref} = 4.02 V,$	TLC5602M	3.919	3.98	4.042	V
			T <sub>A</sub> = full range§		TLC5602M	3.919	3.98	4.062	
_	r <sub>O</sub> Output resistance		T <sub>A</sub> = 25°C TLC5602C		60	80	120	Ω	
10			T <sub>A</sub> = full range§ TLC5602M						
Ci	Input capacitance	$f_{clock} = 1 \text{ MHz},  T_A = 25^{\circ}\text{C}$				15		pF	
I <sub>DD</sub> Supply current			f <sub>clock</sub> = 20 MHz, V <sub>ref</sub> = V <sub>DD</sub> -0.95 V				16	25	mA

<sup>‡</sup> All typical values are at  $V_{DD} = 5 \text{ V}$  and  $T_A = 25^{\circ}\text{C}$ .

### operating characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST COND	MIN	TYP <sup>†</sup>	MAX	UNIT	
E <sub>L(adj)</sub>	Linearity error, best-straight-line	T <sub>A</sub> = full range‡	TLC5602C			±0.2%	
		T <sub>A</sub> = 25°C	TLC5602M			±0.2%	
		T <sub>A</sub> = full range‡	TLC3002W			±0.4%	
EL	Linearity error, end point			=	±0.15%		
E <sub>D</sub>	Linearity error, differential					±0.2%	
G <sub>diff</sub>	Differential gain	NTSC 40-IRE modulated ramp,			0.7%		
fdiff	Differential phase	$f_{clock} = 14.3 \text{ MHz},  Z_L \ge 75 \text{ k}\Omega$			0.4°		
t <sub>pd</sub>	Propagation delay time, CLK to analog output	C <sub>L</sub> = 10 pF			25		ns
t <sub>S</sub>	Settling time to within 1/2 LSB	C <sub>L</sub> = 10 pF			30		ns

<sup>&</sup>lt;sup>†</sup> All typical values are at  $V_{DD} = 5 \text{ V}$  and  $T_A = 25^{\circ}\text{C}$ .

<sup>§</sup> Full range for the TLC5602C is 0°C to 70°C, and full range for the TLC5602M is –55°C to 125°C.

<sup>‡</sup> Full range for the TLC5602C is 0°C to 70°C, and full range for the TLC5602M is -55°C to 125°C.

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#### PARAMETER MEASUREMENT INFORMATION

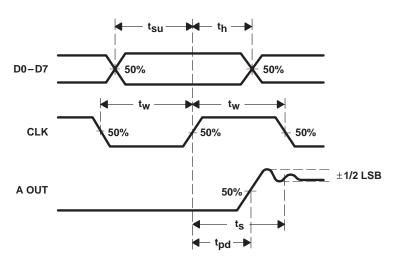


Figure 1. Voltage Waveforms

#### TYPICAL CHARACTERISTICS

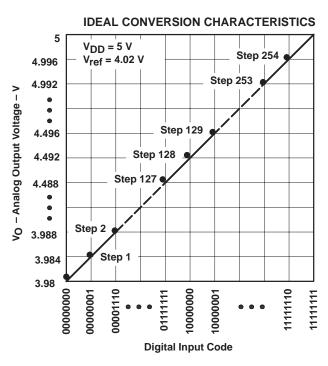
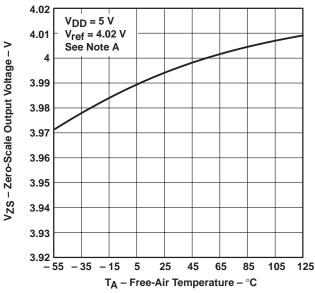


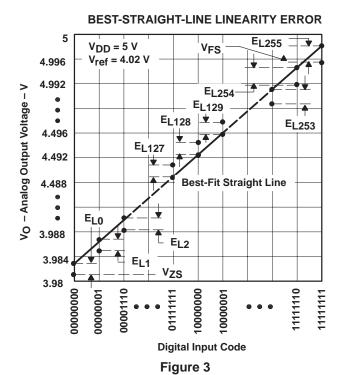
Figure 2

# ZERO-SCALE OUTPUT VOLTAGE vs FREE-AIR TEMPERATURE



NOTE A:  $V_{\text{ref}}$  is relative to ANLG GND.  $V_{\text{DD}}$  is the voltage between ANLG  $V_{\text{DD}}$  and DGTL  $V_{\text{DD}}$  tied together and ANLG GND and DGTL GND tied together.

Figure 4



#### OUTPUT RESISTANCE vs FREE-AIR TEMPERATURE

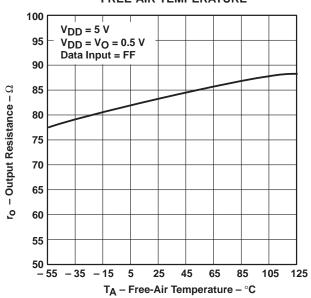


Figure 5



ZERO-SCALE OUTPUT VOLTAGE

#### **TYPICAL CHARACTERISTICS**

#### **SUPPLY CURRENT** FREE-AIR TEMPERATURE 21 $V_{DD} = 5V$ $V_{ref} = 4.02 V$ f<sub>clock</sub> = 20 MHz 20 IDD - Supply Current - mA 19 18 17 16 - 55 - 35 65 - 15 5 25 45 85 105 125 T<sub>A</sub> – Free-Air Temperature – °C

#### **REFERENCE VOLTAGE** $V_{DD} = 5 V$ T<sub>A</sub> = 25°C See Note A 4.8 Vzs - Zero-Scale Output Voltage - V 4.6 4.4 4.2 3.8 3.6 3.4 3.4 3.8 4.2 4.4 4.8 5

NOTE A:  $V_{\text{ref}}$  is relative to ANLG GND.  $V_{\text{DD}}$  is the voltage between ANLG  $V_{\text{DD}}$  and DGTL  $V_{\text{DD}}$  tied together and ANLG GND and DGTL GND tied together.

V<sub>ref</sub> – Reference Voltage – V

Figure 6 Figure 7

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#### **APPLICATION INFORMATION**

The following design recommendations benefit the TLC5602 user:

- Physically separate and shield external analog and digital circuitry as much as possible to reduce system noise.
- Use RF breadboarding or RF printed-circuit-board (PCB) techniques throughout the evaluation and production process.
- Since ANLG GND and DGTL GND are not connected internally, these terminals need to be connected
  externally. With breadboards, these ground lines should connect to the power-supply ground through
  separate leads with proper supply bypassing. A good method is to use a separate twisted pair for the analog
  and digital supply lines to minimize noise pickup.
  - Use wide ground leads or a ground plane on the PCB layouts to minimize parasitic inductance and resistance. The ground plane is the better choice for noise reduction.
- ANLG V<sub>DD</sub> and DGTL V<sub>DD</sub> are also separated internally, so they must connect externally. These external
  PCB leads should also be made as wide as possible. Place a ferrite bead or equivalent inductance in series
  with ANLG V<sub>DD</sub> and the decoupling capacitor as close to the device terminals as possible before the ANLG
  V<sub>DD</sub> and DGTL V<sub>DD</sub> leads are connected together on the board.
- Decouple ANLG  $V_{DD}$  to ANLG GND and DGTL  $V_{DD}$  to DGTL GND with a 1- $\mu$ F and 0.01- $\mu$ F capacitor, respectively, as close as possible to the appropriate device terminals. A ceramic chip capacitor is recommended for the 0.01- $\mu$ F capacitor.
- Connect the phase compensation capacitor between COMP and ANLG GND with as short a lead-in as possible.
- The no-connection (NC) terminals on the small-outline package should be connected to ANLG GND.
- Shield ANLG V<sub>DD</sub>, ANLG GND, and A OUT from the high-frequency terminals CLK and D7–D0. Place ANLG GND traces on both sides of the A OUT trace on the PCB.



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